

# FZ44ZL-VB TO262 Datasheet **Power MOSFET**

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	V <sub>DS</sub> (V) 60				
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V 0.015				
Q <sub>g</sub> (Max.) (nC)	110				
Q <sub>gs</sub> (nC)	29				
Q <sub>gd</sub> (nC)	36				
Configuration	Single				

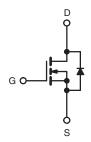
#### **FEATURES**

- · Advanced process technology
- 175 °C operating temperature
- · Fast switching









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ( $T_{\text{C}}$	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	60	V	
Gate-Source Voltage			$V_{GS}$	± 20	V	
Continuous Drain Current f	V at 10 V	T <sub>C</sub> = 25 °C		60		
Continuous Drain Current	$V_{GS}$ at 10 V $T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 100 ^{\circ}\text{C}$	I <sub>D</sub>	50	Α		
Pulsed Drain Current a, e			I <sub>DM</sub>	290		
Linear Derating Factor				1.3	W/°C	
Single Pulse Avalanche Energy b, e			E <sub>AS</sub>	100	mJ	
Maximum Bayyar Dissination	T <sub>C</sub> = 25 °C		ם	190	W	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C		$P_{D}$	3.7		
Peak Diode Recovery dV/dt c, e			dV/dt	4.5	V/ns	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>sta</sub>	-55 to +175	00	
Soldering Recommendations (Peak temperature) d	for 10 s		_	300	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD}$  = 25 V, Starting  $T_J$  = 25 °C, L = 22  $\mu$ H,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 72 A (see fig. 12). c.  $I_{SD} \le 72$  A,  $I_{AS}$  = 72 A,  $I_{AS}$  = 72 A,  $I_{AS}$  = 72 A,  $I_{AS}$  = 72 A (see fig. 12). d. 1.6 mm from case. e. Uses IRFZ48, SiHFZ48 data and test conditions.

- f. Calculated continuous current based on maximum allowable junction temperature.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB mount) <sup>a</sup>	R <sub>thJA</sub>	-	40	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.8		

#### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					•		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	$V_{GS} = 0$ , $I_D = 250 \mu A$		-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA °	-	0.060	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	1.5	-	3.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zoro Coto Voltago Drain Current		V <sub>DS</sub>	= 60 V, V <sub>GS</sub> = 0 V	-	-	25	μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 48 \text{ V}$	, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C	-	-	250	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 15 A <sup>b</sup>	-	0.015	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	= 25 V, I <sub>D</sub> = 15 A <sup>b</sup>	27	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		3500	-	
Output Capacitance	C <sub>oss</sub>				1300	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 MHz, see fig. 5 °		-	190	-	
Total Gate Charge	Qg			-	-	110	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$	$V_{GS} = 10 \text{ V}$ $I_D = 12 \text{ A}, V_{DS} = 48 \text{ V},$ see fig. 6 and 13 b, c		-	29	nC
Gate-Drain Charge	Q <sub>gd</sub>	see lig. 0 and 13 57		-	-	36	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 30 \text{ V, } I_D = 12 \text{ A,}$ $R_g = 9.1 \ \Omega, \ R_D = 0.34 \ \Omega, \ \text{see fig. } 10^{\text{ b, c}}$		-	8.1	-	ns
Rise Time	t <sub>r</sub>			-	250	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	210	-	
Fall Time	t <sub>f</sub>			-	250	-	
Internal Source Inductance	L <sub>S</sub>	Between lead, and center of die contact		-	7.5	-	nH
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	showing the			-	50°	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	90	
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25  ^{\circ}\text{C},  I_S = 72  \text{A},  V_{GS} = 0  \text{V}^{ \text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	- T <sub>J</sub> = 25 °C, I <sub>F</sub> = 72 A, dl/dt = 100 A/μs <sup>b, c</sup>		-	120	180	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	500	800	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq 300~\mu s$ ; duty cycle  $\leq 2~\%.$  c. Uses VBL1615/FZ44ZL-VB TO262 data and test conditions.

- d. Calculated continuous current based on maximum allowable junction temperature.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

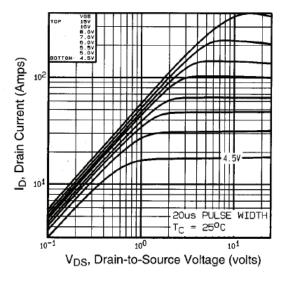


Fig. 1 - Typical Output Characteristics

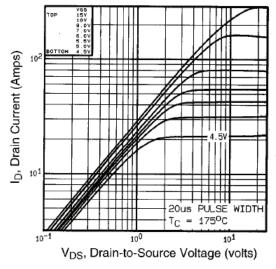


Fig. 2 - Typical Output Characteristics

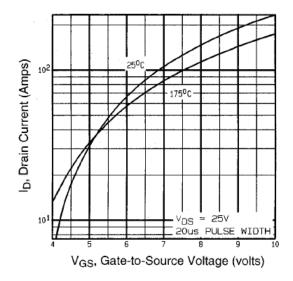


Fig. 3 - Typical Transfer Characteristics

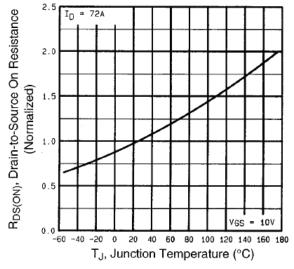


Fig. 4 - Normalized On-Resistance vs. Temperature



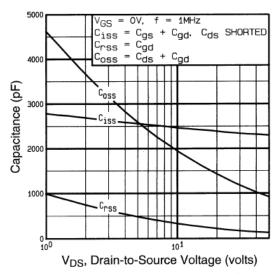


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

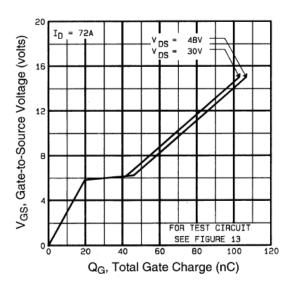


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

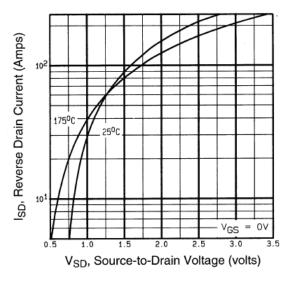


Fig. 7 - Typical Source-Drain Diode Forward Voltage

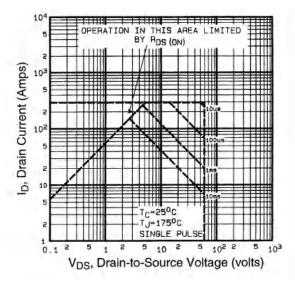


Fig. 8 - Maximum Safe Operating Area



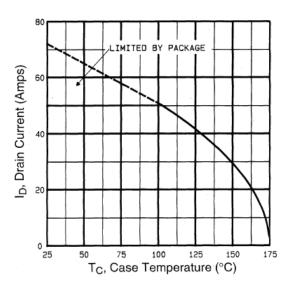


Fig. 9 - Maximum Drain Current vs. Case Temperature

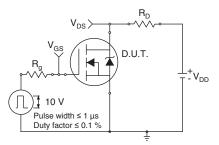


Fig. 10a - Switching Time Test Circuit

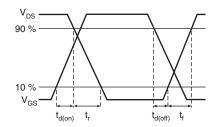
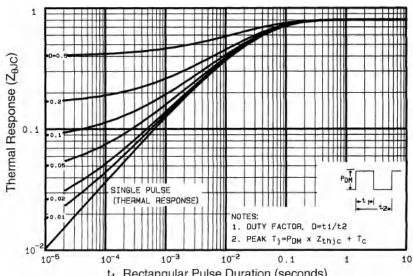


Fig. 10b - Switching Time Waveform



 $t_1,\,Rectangular\,Pulse\,Duration\,(seconds)\\ \label{t1}$  Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

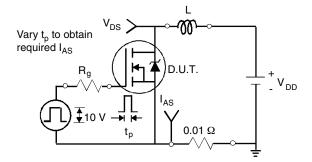


Fig. 12a - Unclamped Inductive Test Circuit

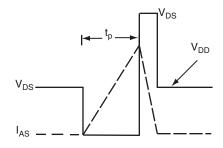


Fig. 12b - Unclamped Inductive Waveforms



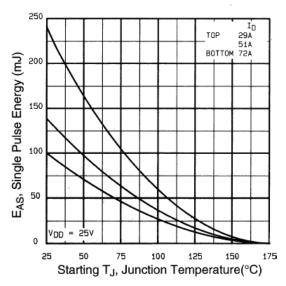


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

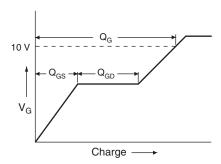


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

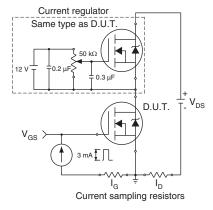
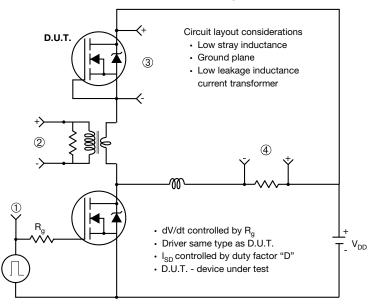


Fig. 13b - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit



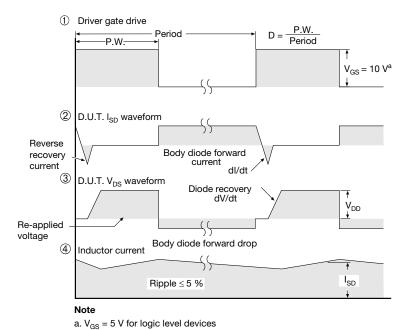
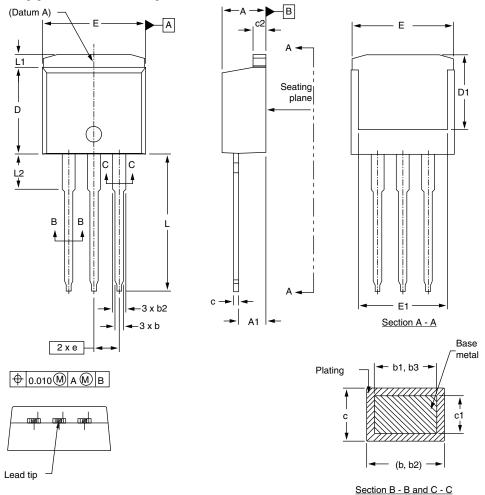


Fig. 14 - For N-Channel



### I<sup>2</sup>PAK (TO-262) (HIGH VOLTAGE)



	MILLIN	METERS	INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	2.03	3.02	0.080	0.119
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D	8.38	9.65	0.330	0.380
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54	BSC	0.100	BSC
L	13.46	14.10	0.530	0.555
L1	-	1.65	-	0.065
L2	3.56	3.71	0.140	0.146

Scale: None

ECN: S-82442-Rev. A, 27-Oct-08

DWG: 5977

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm per side. These dimensions are measured at the outmost extremes of the plastic body.
- 3. Thermal pad contour optional within dimension E, L1, D1, and E1.
- 4. Dimension b1 and c1 apply to base metal only.



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BXP4N65F AOL1454G WMJ80N60C4 BXP2N20L BXP2N65D BXT1150N10J BXT1700P06M TSM60NB380CP ROG RQ7L055BGTCR
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